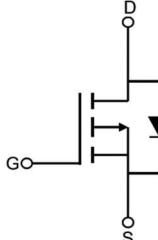


Description

Features	Application
<ul style="list-style-type: none"> ● $V_{DS} = -40V$, $I_D = -15A$ $R_{DS(ON)} < 35m\Omega$ @ $V_{GS} = -10V$ $R_{DS(ON)} < 56m\Omega$ @ $V_{GS} = -4.5V$ ● Advanced Trench Technology ● Excellent $R_{DS(ON)}$ and Low Gate Charge ● Lead free product is acquired 	<ul style="list-style-type: none"> ● PWM Applications ● Load Switch ● Power Management



TO-252



Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	Reel Size	Reel (PCS)	Per Carton (PCS)
VSM15P04-T2	VSM15P04	TAPING	TO-252	13inch	2500	25000

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise specified)

Symbol	Parameter		Max.	Units
V_{DSS}	Drain-Source Voltage		-40	V
V_{GSS}	Gate-Source Voltage		± 20	V
I_D	Continuous Drain Current	$T_C = 25^\circ C$	-15	A
		$T_C = 100^\circ C$	-10	A
I_{DM}	Pulsed Drain Current ^{note1}		-60	A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}		38	mJ
P_D	Power Dissipation	$T_C = 25^\circ C$	15	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case		10	$^\circ C/W$
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +175	$^\circ C$

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D = -250\mu\text{A}$	-40	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -40\text{V}$, $V_{GS}=0\text{V}$	-	-	-1	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS}=0\text{V}$, $V_{GS} = \pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D = -250\mu\text{A}$	-1.0	-1.6	-2.5	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS} = -10\text{V}$, $I_D = -15\text{A}$	-	27	35	$\text{m}\Omega$
		$V_{GS} = -4.5\text{V}$, $I_D = -10\text{A}$	-	40	56	
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = -20\text{V}$, $V_{GS}=0\text{V}$, $f=1.0\text{MHz}$	-	1273	-	pF
C_{oss}	Output Capacitance		-	132	-	pF
C_{rss}	Reverse Transfer Capacitance		-	98	-	pF
Q_g	Total Gate Charge	$V_{DS} = -20\text{V}$, $I_D = -8\text{A}$, $V_{GS} = -10\text{V}$	-	24	-	nC
Q_{gs}	Gate-Source Charge		-	4.3	-	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	5.2	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = -20\text{V}$, $I_D = -15\text{A}$, $V_{GS} = -10\text{V}$, $R_{\text{GEN}} = 2.5\Omega$	-	11	-	ns
t_r	Turn-on Rise Time		-	16	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	29	-	ns
t_f	Turn-off Fall Time		-	15	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_s	Maximum Continuous Drain to Source Diode Forward Current	-	-	-15	-	A
I_{sM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	-60	-	A
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}$, $I_s = -15\text{A}$	-	-0.8	-1.2	V
trr	Reverse Recovery Time	$V_{GS} = 0\text{V}$, $I_s = -15\text{A}$, $di/dt = 100\text{A}/\mu\text{s}$	-	31	-	ns
Qrr	Reverse Recovery Charge		-	23	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition: $T_J = 25^\circ\text{C}$, $V_{DD} = -20\text{V}$, $V_G = -10\text{V}$, $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = -12.4\text{A}$

3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$

Typical Performance Characteristics

Figure 1: Output Characteristics

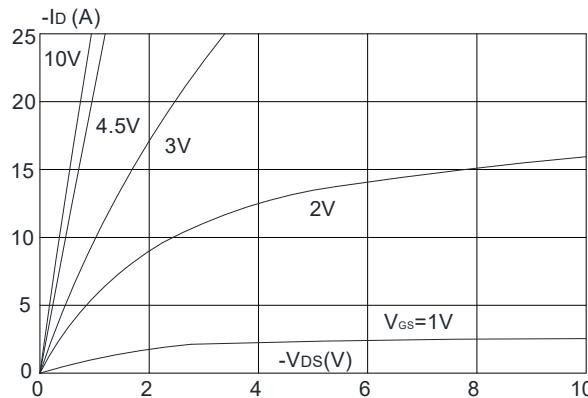


Figure 3: On-resistance vs. Drain Current

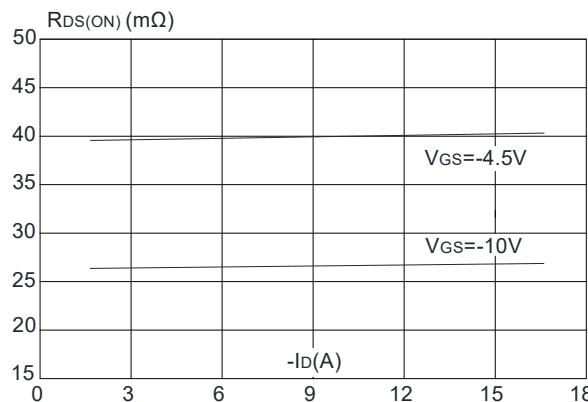


Figure 5: Gate Charge Characteristics

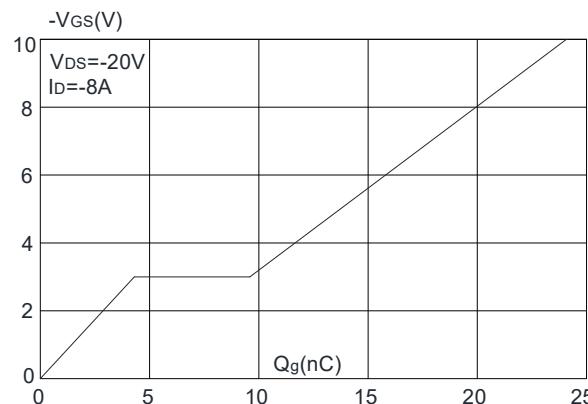


Figure 2: Typical Transfer Characteristics

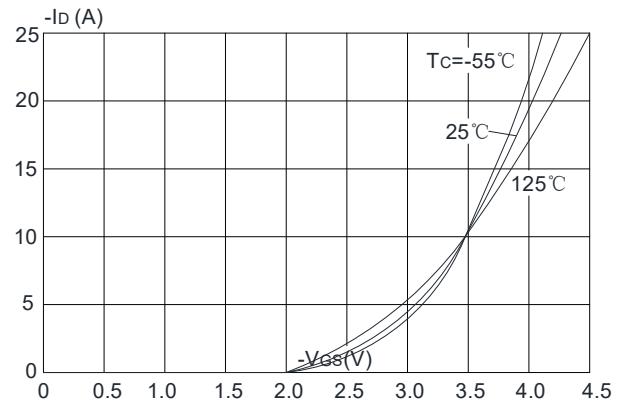


Figure 4: Body Diode Characteristics

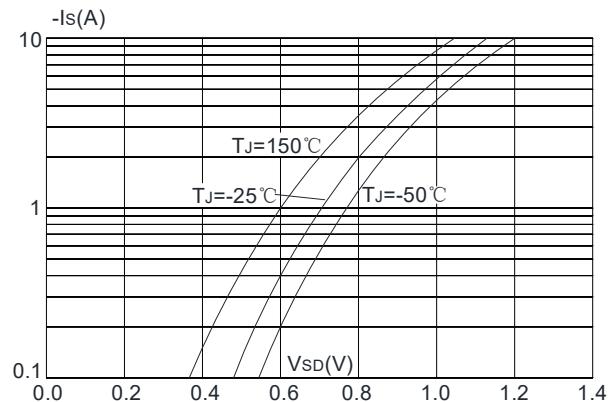


Figure 6: Capacitance Characteristics

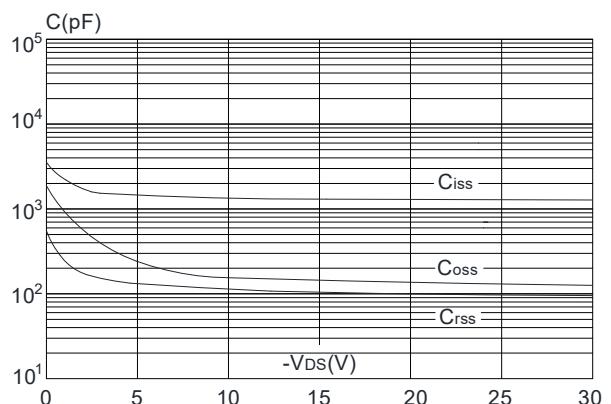


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

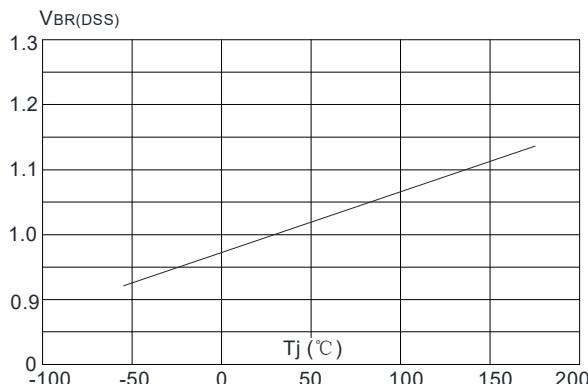


Figure 8: Normalized on Resistance vs. Junction Temperature

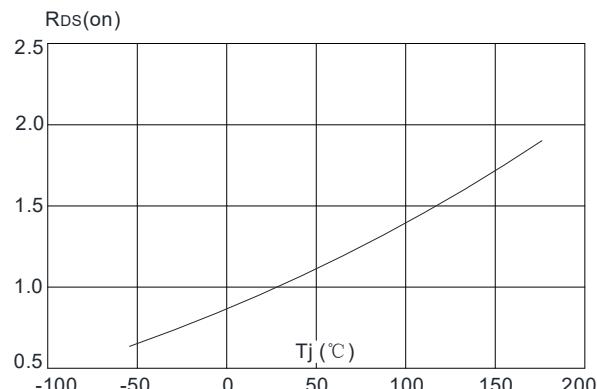


Figure 9: Maximum Safe Operating Area

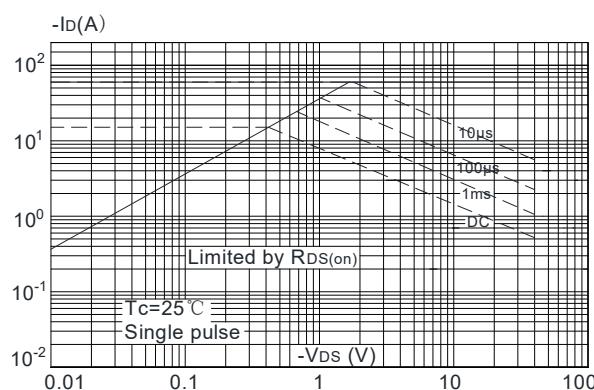


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

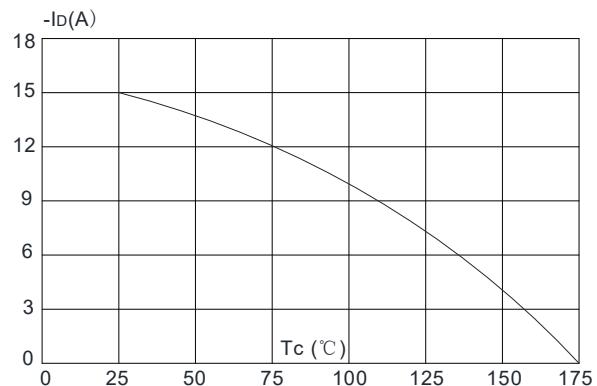
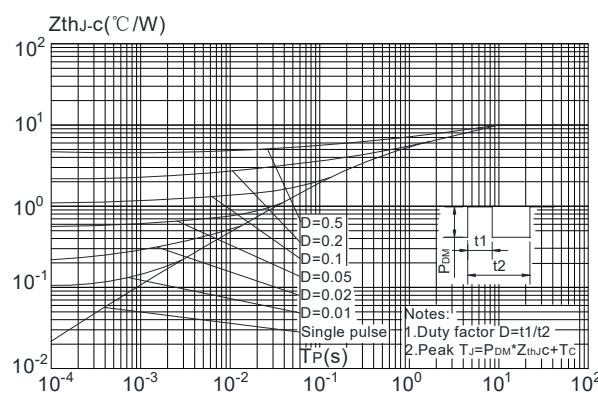
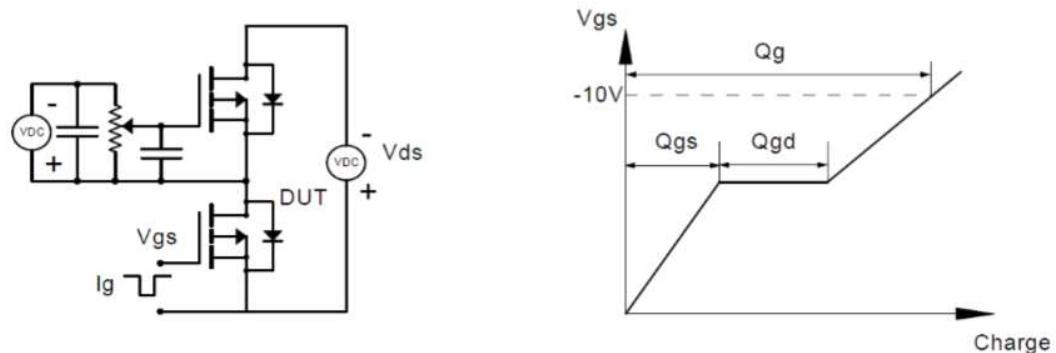


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

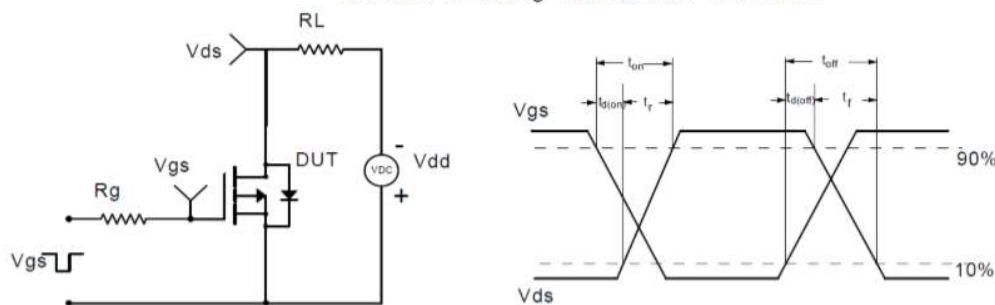


Test Circuit

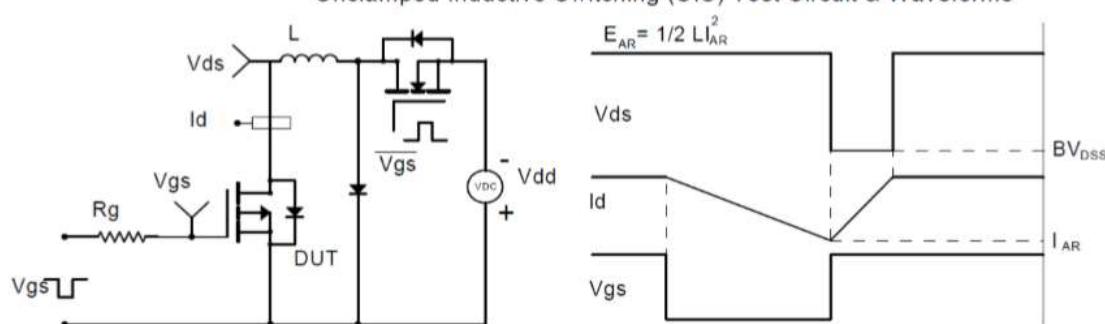
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

